



LIST OF RELATED CASES

	<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
AQA.	208546US2S	09/853,661	05/14/01	TANAKA
AQA.	227579US2S	10/230,119	08/29/02	TANAKA
AQA.	232835US2S	10/354,048	01/30/03	YAMAGUCHI et al.
AQA.	237756US2	10/437,060	05/14/03	TANAKA
AQA.	243492US2S	10/677,260	10/03/03	TANAKA et al.
AQA.	251363US2*	10/814,246	04/01/04	OKUNO et al.

am o. am 1 May 05

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251363US2		SERIAL NO. 10/814,246	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takahiro OKUNO, et al.			
				FILING DATE April 1, 2004		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
A.O.A.	AO	2003-204066 (2002-1784)	07/18/2003	JAPAN (with English Abstract)			X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
A.O.A.	AW	I. OMURA, et al., IEEE Transactions on Electron Devices, vol. 46, no. 1, pages 237-244, "OSCILLATION EFFECTS IN IGBT's RELATED TO NEGATIVE CAPACITANCE PHENOMENA", January 1999					
A.O.A.	AX	I. OMURA, et al., Proceedings of ISPSD, pages 25-28, "IEGT DESIGN CONCEPT AGAINST OPERATION INSTABILITY AND ITS IMPACT TO APPLICATION", May 25, 2000					
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>am o. m</i>					Date Considered <i>1 May 2005</i>		
*Examiner: initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							